



Figure 1. Supplementary synchrotron X-ray diffraction patterns of (a) modified CaFe₂O₄-type FeCr₂O₄, (b) CaTi₂O₄-type FeCr₂O₄ and (c) modified ludwigite-type Fe₂Cr₂O₅ at ambient conditions. The diffraction patterns in the whole 2θ range up to 75° were used for Rietveld refinements. Insets of (a)-(c) are the results of Rietveld refinements in the high angle regions. Data points and solid lines show the observed and the calculated profiles, respectively, and the difference between them is shown at the bottom. Bragg peak positions are marked by small ticks. These lines are for main phases, Cr₂O₃ eskolaite and Re from top to bottom.